

# **INITIAL PRODUCT/PROCESS CHANGE NOTIFICATION #16935**

Generic Copy

Issue Date: 27-Nov-2012

<u>TITLE:</u> Initial Notification of Qualification of ON Semiconductor Philippines Inc. for Assembly of 8 Lead TSSOP 4.4x3.0mm Packages.

PROPOSED FIRST SHIP DATE: 27-Mar-2013

AFFECTED CHANGE CATEGORY(S): ON Semiconductor Assembly

#### FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:

Contact your local ON Semiconductor Sales Office or <Shao.Sia@onsemi.com>

### **NOTIFICATION TYPE:**

Initial Product/Process Change Notification (IPCN)

First change notification sent to customers. IPCNs are issued at least 120 days prior to implementation of the change. An IPCN is an advance notification about an upcoming change and contains general information regarding the change details and devices affected. It also contains the preliminary reliability qualification plan.

The completed qualification and characterization data will be included in the Final Product/Process Change Notification (FPCN).

This IPCN notification will be followed by a Final Product/Process Change Notification (FPCN) at least 90 days prior to implementation of the change.

#### **DESCRIPTION AND PURPOSE:**

IPCN# 16935 is available at <a href="www.onsemi.com">www.onsemi.com</a>. This is to notify customers of the assembly site transfer of 8 Lead TSSOP8 4.4x3.0mm package. Historically, the device listed was being assembled at Amkor located in Laguna, Philippines. At the expiration of Initial and Final PCN, the device listed will be assembled at ON Semiconductor located in Cavite, Philippines. The change also includes MSL 1/260C qualification.

Issue Date: 27-Nov-2012 Rev. 06-Jan-2010 Page 1 of 2



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## **QUALIFICATION PLAN:**

Test Conditions

MSL 1 Preconditioning (PC) 3xIR @ 260 °C

Temp Cycling + preconditioning (TC+PC)

Temp= -65 °C to +150 °C; for 500 cycles

Autoclave + preconditioning (AC+PC) Temp= +121 °C; RH=100%, 15 PSIG

for 96 hours

High Temp Storage Life (HTSL)

Temp= +150 OC for 1,008 Hours

Scanning Acoustic Tomography (SAT)

ON Semiconductor SAT Guidelines

Wire Bond Shear Test (WBS) Cpk>1.33

Wire Bond Pull Test (BPS) Cpk>1.33

Solderability (SD) >95% lead coverage

Physical Dimensions (PD) Cpk>1.33

# **List of affected General Parts:**

NB2305AI1DTG NB2305AI1DTR2G NB2305AI1HDTG NB2305AI1HDTR2G NB3N2304NZDTG NB3N2304NZDTR2G

Issue Date: 27-Nov-2012 Rev. 06-Jan-2010 Page 2 of 2